

Search Notes

Application/Control No.

10/532,845

Examiner

Y. Lee

Applicant(s)/Patent under Reexamination

LU ET AL.

Art Unit

2621

SEARCHED

Class	Subclass	Date	Examiner
375	240.01 240.12 240.13 240.29	6/18/2008	YL
H04N	7/12		
update	search	3/3/2009	YL
update	search	7/21/2009	YL
update	search	12/9/2009	YL
update	search	4/27/2010	YL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner